

DOPED SEMICONDUCTORS

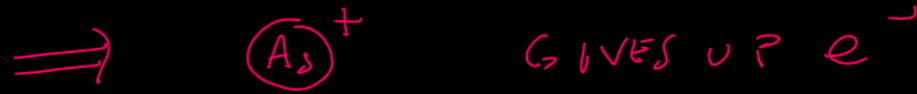
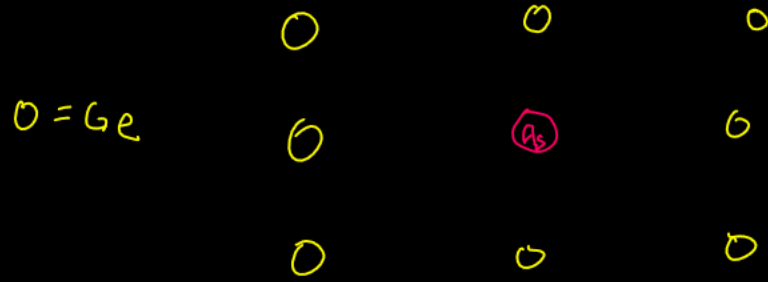
$$\Delta n = n - p \implies \Delta n \leftrightarrow \mu \quad \Delta n_i = 0$$

$$\Delta n = ?$$

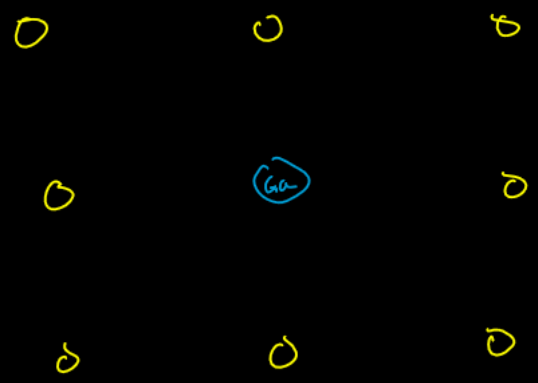
TYPES OF IMPURITIES

DONOR IMPURITIES - GIVE UP ELECTRONS (DONORS) n-DOPED

As → GROUP V



ACCEPTORS - TAKE ON EXTRA ELECTRON p-DOPED



"ABSORBS" $e^- \Rightarrow$
GIVES UP HOLE

COMPENSATED SEMICONDUCTORS (BOTH n & p DEFECTS)

TO CALCULATE $\Delta n \Rightarrow$ IMPURITY LEVEL ENERGIES

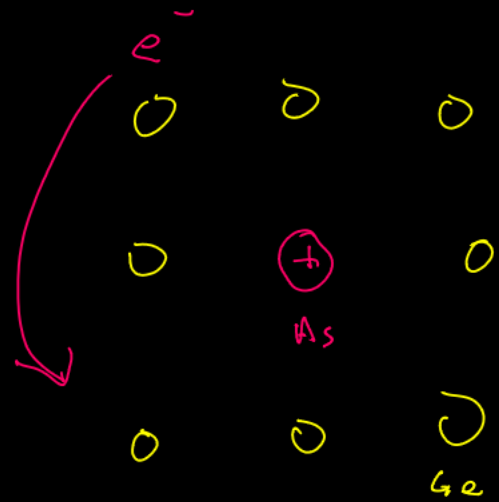
① SHALLOW LEVEL IMPURITIES (AS OPPOSED TO DEEP LEVELS)

BEHAVE LIKE HYDROGEN ATOMS



$R_H = 13.6 \text{ eV}$

e^-



(A) $m_e^* \rightarrow m_e$ (REPLACE e^- MASS BY m_e^*)
 ($m_h^* \rightarrow$ FOR ACCEPTORS) $m^* \sim 0.1 - 0.01 m_e$

(B) DIELECTRIC CONSTANT FOR MATERIAL
 $\epsilon \sim 10 - 20$ FREE SPACE

TAKE "1/2" STATES OUT OF BOTTOM CONDUCTION (DONORS)
 (TOP VALENCE ACCEPTORS)

BOHR RADIUS

($\frac{a_0}{\epsilon}$) $\rightarrow \frac{e^2}{\epsilon r}$
 \uparrow
 DIELECTRIC MATERIAL

$$\frac{m}{m^*} \epsilon \frac{\hbar^2}{m e^2} \Rightarrow \frac{\epsilon \hbar^2}{m^* e^2}$$

$\underbrace{\hspace{2cm}}_{a_0}$
 0.53 \AA

$\epsilon =$ DIELECTRIC FUNCTION

RYD BERG ENERGY

$$\left(\frac{m^*}{m_e} \right) \left(\frac{m_e^4}{2 \hbar} \right)$$

$R_y^0 = 13.6 \text{ eV}$

GaAs

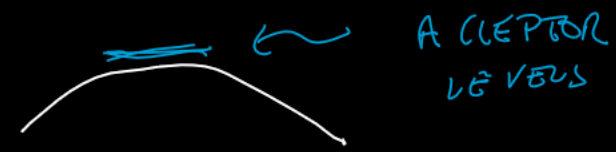
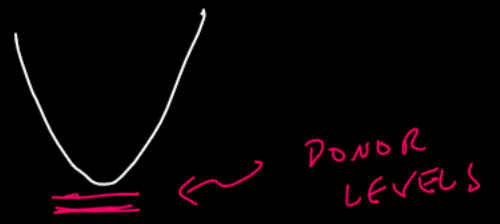
$m^* = 0.067 m_e$

$E = 13.6$



$a = 104 \text{ \AA}$ LARGE!

$R_y = 5.3 \text{ meV}$ (SMALL)



SHALLOW LEVELS \Leftrightarrow HYDROGENIC LEVELS

THERMAL EQUILIBRIUM # DONORS @ A GIVEN SITE

$$\langle n \rangle = \frac{\sum_j N_j e^{-B(E_j - \mu N_j)}}{\sum_j e^{-B(E_j - \mu N_j)}}$$

↑
AVE #
e⁻ @ DONOR
SITE

CAN HAVE 0, ↑, ↓, ↑↓

2 ELECTRONS
NORMALLY IGNORE ↑↓
BECAUSE COULOMB REPELUSION
IS TOO HIGH!

$$\langle n \rangle = \frac{2e^{-B(E_d - \mu)}}{1 + 2e^{-B(E_d - \mu)}}$$

||
e⁻
ON DONOR
SITE

$$\langle n \rangle = \frac{1}{\frac{1}{2} e^{B(\epsilon_d - \mu)} + 1}$$

↑
NOTE $\frac{1}{2}$.

THIS IS NOT FERMI-DIRAC
FUNCTION WITH EXTRA $\frac{1}{2}$)

SYSTEM IS HIGHLY
INTERACTING

IN LIMIT $\epsilon_d - \mu \gg k_B T \Rightarrow \langle n \rangle \sim 2 e^{-B(\epsilon_d - \mu)} \ll 1$

$\langle n \rangle$ SMALL \Rightarrow DONORS ARE IONIZED!

$\langle p \rangle$ SMALL \Rightarrow ACCEPTORS "IONIZED" \Rightarrow (HOLES)

$$\Delta n = n_c - p_v \approx N_d - N_a$$

\updownarrow
 μ

$$R_{sh} \approx \frac{1}{nec}$$

METALS \Rightarrow CARRIER DENSITY NOT SENSITIVE TO T

$$\sigma = \frac{ne^2\tau}{m} \quad \vec{j} = \sigma \vec{E}$$

SEMICONDUCTORS \Rightarrow CARRIER DENSITY, STRONGLY T DEP,
(DOPANTS)

$$\mu \equiv \frac{|v|}{E}$$

MOBILITY VELOCITY
ELECTRIC FIELD

$$\vec{J} = (n e \mu_e + p e \mu_h) E$$

$$\mu_e = \frac{e \tau_e}{m_e^*}$$

$$\mu_h = \frac{e \tau_h}{m_h^*}$$

τ = SCATTERING TIME

m_{eh} = EFFECTIVE MASSES

	ROOM T	MOBILITIES
	e	h
GaAs	8000	300
DIAMOND	1800	1200
Si	1350	480
Ge	3600	1800
InAs	30,000	450

WHY $\mu_h < \mu_e$?

$$m_h^* > m_e^*$$

$$\tau_h < \tau_e$$

